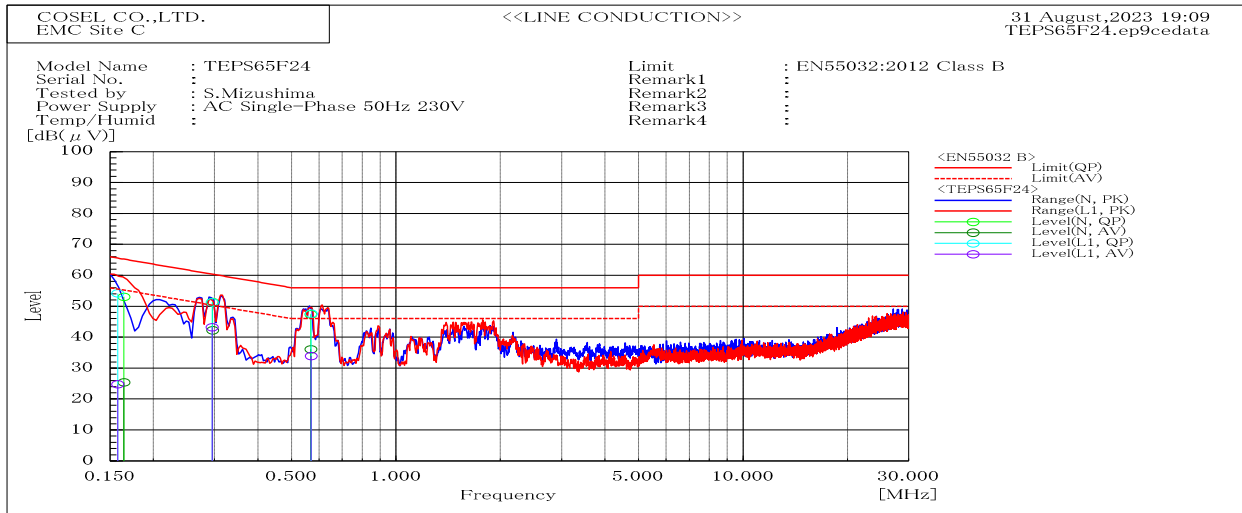
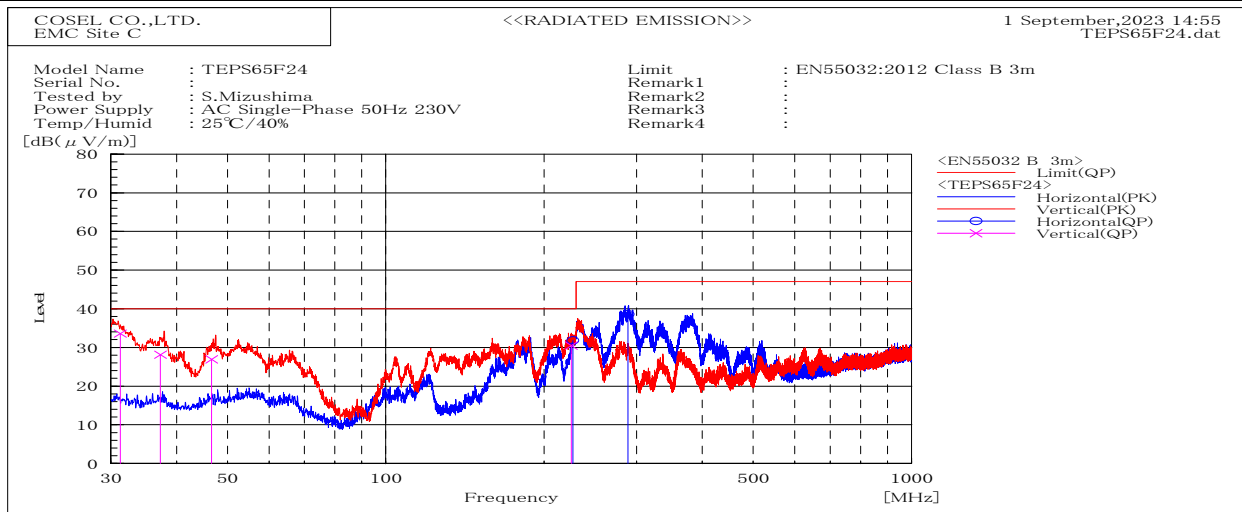


DATA SHEET		Date	12-Oct-23
Model	TEPS65F24	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Mizushima



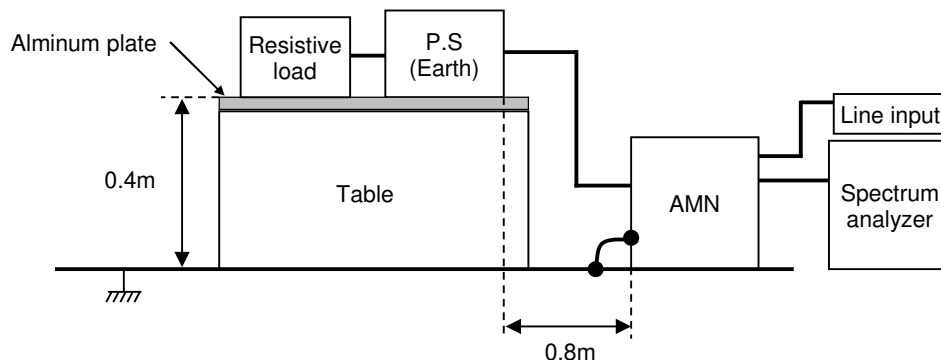
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.165	N	53	25.4	65.2	55.2	12.2	29.8	Pass	
0.296	N	51.3	42.2	60.3	50.3	9	8.1	Pass	
0.569	N	47.4	36.1	56	46	8.6	9.9	Pass	
0.158	L1	54.1	24.8	65.6	55.6	11.5	30.8	Pass	
0.295	L1	51.2	43.2	60.4	50.4	9.2	7.2	Pass	
0.57	L1	47.6	33.9	56	46	8.4	12.1	Pass	



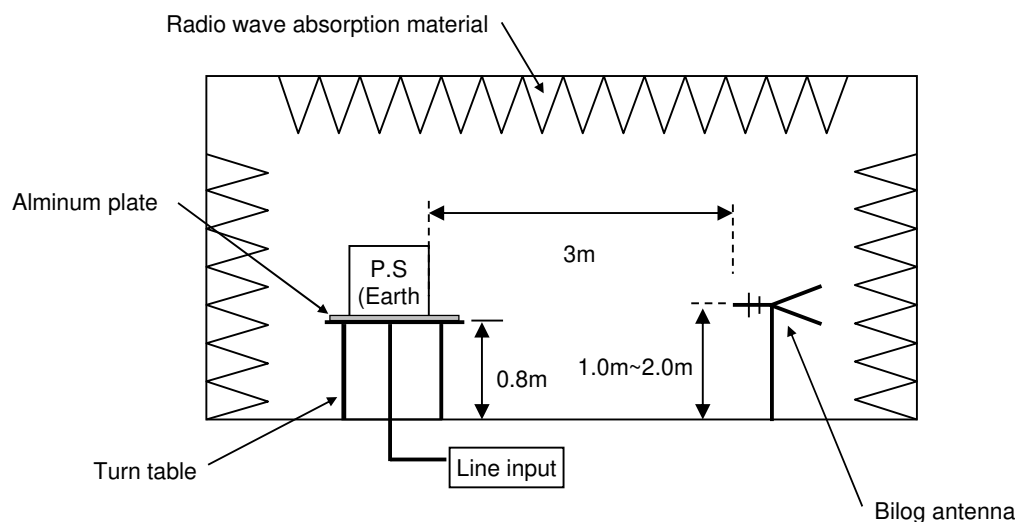
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP		QP				
31.253	V	Stable	33.6	40	40	6.4	Pass	100.4	246.5	
37.266	V	Stable	28.1	40	40	11.9	Pass	100.4	222.3	
46.67	V	Stable	26.9	40	40	13.1	Pass	100.6	59.5	
225.251	V	Stable	30.5	40	40	9.5	Pass	100.6	355.5	
226.953	H	Stable	31.8	40	40	8.2	Pass	133.1	58.9	
289.034	H	Stable	38.6	47	47	8.4	Pass	115.6	262.9	

DATA SHEET		Date	12-Oct-23
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Mizushima

### 1. Line conduction

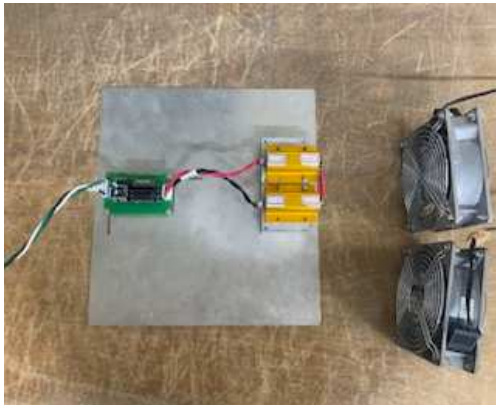


### 2. Radiated emission



**Conditions**

Test : EMI  
Model Nam: TEPS65F24

**1.LINE CONDUCTION****2.RADIATED EMISSION**